

**Notice of References Cited**

Application/Control No.

10/060,022

Applicant(s)/Patent Under  
Reexamination  
SONNIER ET AL.

Examiner

Barbara P. Badio, Ph.D.

Art Unit

1612

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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	K	US-			
	L	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 99/42471	08-1999	WO	Wong et al.	-
	O					
	P					
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**NON-PATENT DOCUMENTS**

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